

“Control of Knock-On Damage for 3D Atomic Scale Quantification of Nanostructures: Making Every Electron Count in Scanning Transmission Electron Microscopy”. Van Aert S, De Backer A, Jones L, Martinez GT, Béch   A, Nellist PD, Physical review letters **122**, 066101 (2019). <http://doi.org/10.1103/PhysRevLett.122.066101>